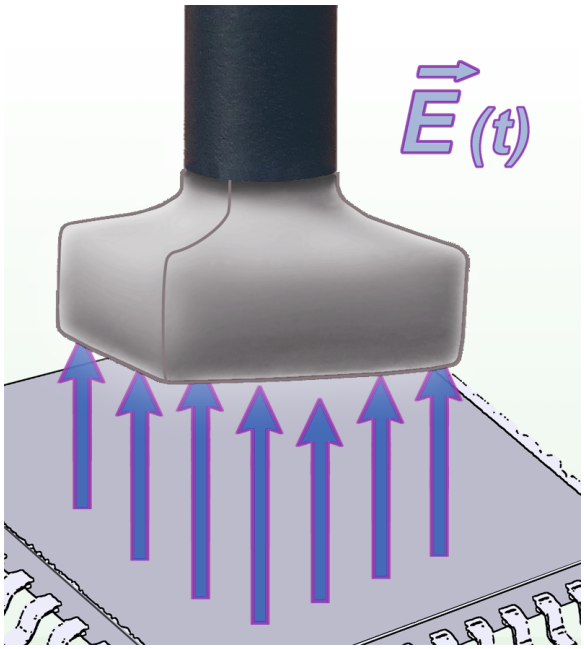
XF-E 09s

E-Field Probe 30 MHz up to 6 GHz

LANGER
EMV-Technik



Short description

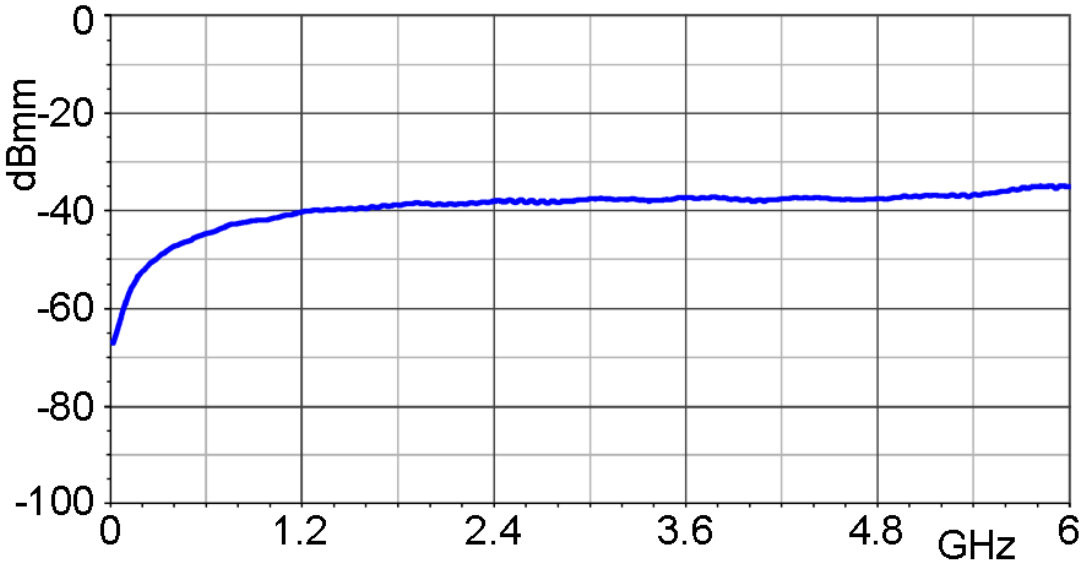
The electrode on the probe head of the XF-E 09s near-field probe detects electrical fields which, for example are decoupled above the IC's surface. The probe's resolution allows for measurements at a distance of 0.5 mm upto 10 mm above an assembly.

The XF-E 09s is a passive near-field probe. In principle it has the same structure as the XF-E 04s probe. To measure, the E-field probe is positioned above or onto components and printed circuit boards. It has a current attenuating sheath and, therefore, its upper half is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E-field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 6 GHz
Probe head dimensions	≈ (10 x 10) mm
Connector - output	SMA, female, jack

Frequency response [dBµV] / [dBµV/mm]



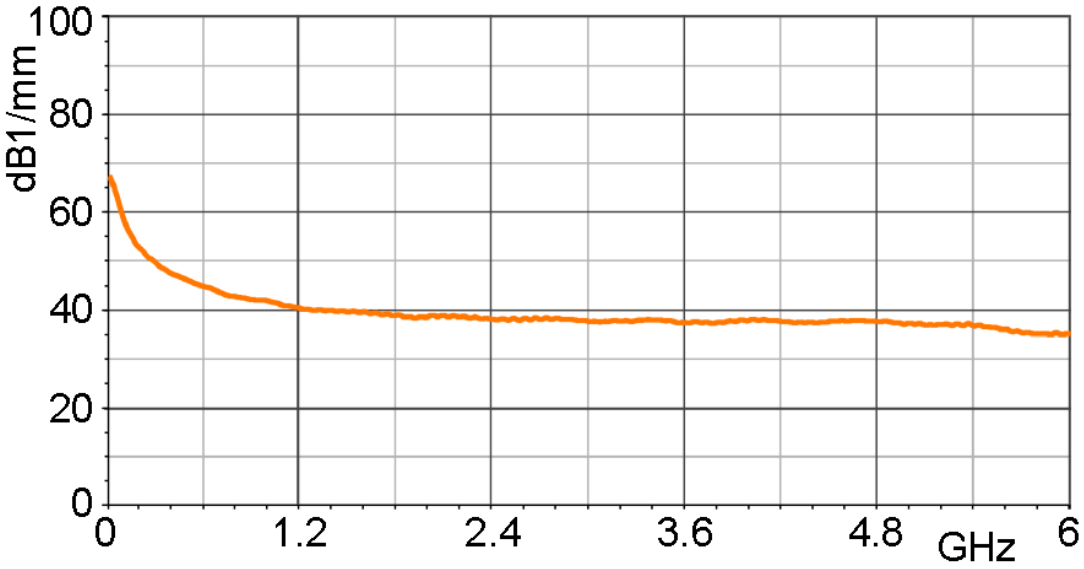
ES France - Département Tests & Mesures
127 rue de Buzenval BP 26 - 92380 Garches
Tél. 01 47 95 99 45
Fax. 01 47 01 16 22
e-mail : tem@es-france.com
Site Web : www.es-france.com

XF-E 09s

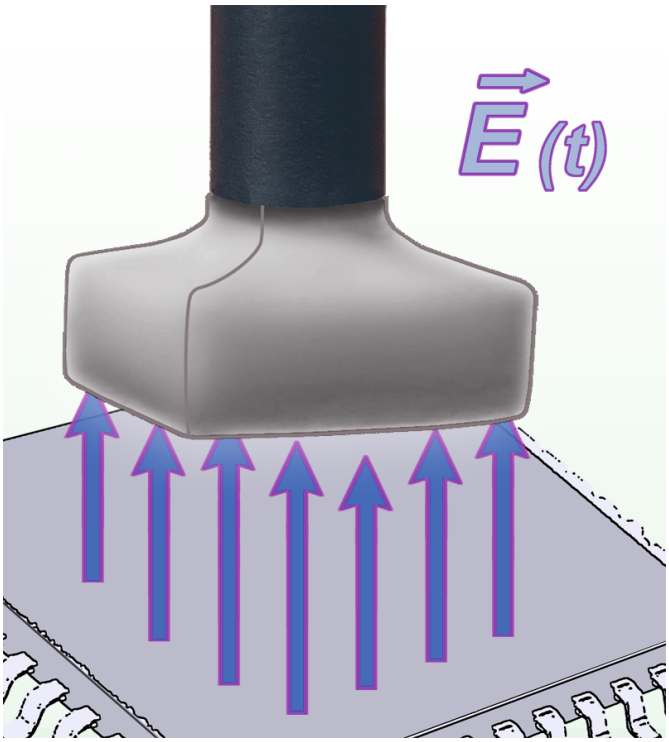
E-Field Probe 30 MHz up to 6 GHz

LANGER EMV-Technik

E- field correction curve [dBµV/mm] / [dBµV]



Measuring principles



ES France - Département Tests & Mesures
127 rue de Buzenval BP 26 - 92380 Garches
Tél. 01 47 95 99 45
Fax. 01 47 01 16 22
e-mail : tem@es-france.com
Site Web : www.es-france.com

XF-E 09s

E-Field Probe 30 MHz up to 6 GHz

LANGER
EMV-Technik

Probe head

ES France - Département Tests & Mesures
127 rue de Buzenval BP 26 - 92380 Garches
Tél. 01 47 95 99 45
Fax. 01 47 01 16 22
e-mail : tem@es-france.com
Site Web : www.es-france.com